

Notice of References Cited	Application/Control No. 10/017,265		Applicant(s)/Patent Under Reexamination KAKIVAYA ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	C	US-2004/0093344	05-2004	Berger et al.	707/102
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	User Interface Markup Language (UIML) Draft Specification, 17 January 2000, Copyright Harmonia, Inc., Language Version 2.0a.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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